

### SEMITRANS<sup>®</sup> 2

### SKM150GB12V

#### Features

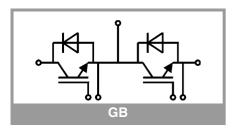
- V-IGBT = 6. Generation Trench V-IGBT (Fuji)
- CAL4 = Soft switching 4. Generation CAL-diode
- Insulated copper baseplate using DBC technology (Direct Copper Bonding)
- Increased power cycling capability
- With integrated gate resistor
- UL recognized, file no. E63532
- Lowest switching losses at High di/dt

### **Typical Applications\***

- AC inverter drives
- UPS
- Electronic welders

#### Remarks

- Case temperature limited to T<sub>c</sub> = 125°C max.
- Recommended  $T_{op} = -40 \dots +150^{\circ}C$
- Product reliability results valid for  $T_j = 150^{\circ}C$



|                     | Maximum Ratin  | 30                      | 1       |         |      | Unit |
|---------------------|--|-------------------------|---------|---------|------|------|
| Symbol              | Conditions   |                         | Values  |         |      |      |
| IGBT                |  |                         |         |         |      |      |
| V <sub>CES</sub>    | T <sub>j</sub> = 25 °C   |                         |         | 1200    |      | V    |
| l <sub>C</sub>      | T <sub>j</sub> = 175 °C  | T <sub>c</sub> = 25 °C  |         | 231     |      | Α    |
|                     |  | T <sub>c</sub> = 80 °C  |         | 176     |      | Α    |
| I <sub>Cnom</sub>   |  |                         |         | 150     |      | Α    |
| I <sub>CRM</sub>    | $I_{CRM} = 3 \times I_{Cnom}$                                  |                         |         | 450     |      | Α    |
| $V_{\text{GES}}$    |  |                         |         | -20 20  |      | V    |
| t <sub>psc</sub>    | $V_{CC} = 720 V$<br>$V_{GE} \le 15 V$<br>$V_{CES} \le 1200 V$  | T <sub>j</sub> = 125 °C |         | 10      |      | μs   |
| Tj                  |  |                         |         | -40 175 |      | °C   |
| Inverse d           | iode   |                         |         |         |      |      |
| l <sub>F</sub>      | T <sub>j</sub> = 175 °C  | T <sub>c</sub> = 25 °C  |         | 189     |      | Α    |
|                     |  | T <sub>c</sub> = 80 °C  |         | 141     |      | Α    |
| I <sub>Fnom</sub>   |  |                         |         | 150     |      | Α    |
| I <sub>FRM</sub>    | $I_{FRM} = 3 x I_{Fnom}$                                       |                         |         | 450     |      | Α    |
| I <sub>FSM</sub>    | $t_p = 10 \text{ ms}, \sin 180^\circ, T_j = 25 ^\circ\text{C}$ |                         |         | 900     |      |      |
| Tj                  |  |                         | -40 175 |         | °C   |      |
| Module              |  |                         |         |         |      |      |
| I <sub>t(RMS)</sub> |  |                         |         | 200     |      | Α    |
| T <sub>stg</sub>    |  |                         |         | -40 125 |      | °C   |
| Visol               | AC sinus 50 Hz, t = 1 min                                      |                         |         | 4000    |      |      |
| Characte            | eristics   |                         |         |         |      |      |
| Symbol              | Conditions   |                         | min.    | typ.    | max. | Uni  |
| IGBT                |  |                         |         |         |      |      |

| Symbol  | Conditions   |                         | min. | typ. | max. | Unit |
|---|--|-------------------------|------|------|------|------|
| IGBT  |  |                         |      |      |      |      |
| V <sub>CE(sat)</sub>                                | I <sub>C</sub> = 150 A   | T <sub>j</sub> = 25 °C  |      | 1.75 | 2.20 | V    |
|   | V <sub>GE</sub> = 15 V<br>chiplevel  | T <sub>j</sub> = 150 °C |      | 2.20 | 2.48 | V    |
| V <sub>CE0</sub> chiplevel                          | T <sub>j</sub> = 25 °C   |                         | 0.94 | 1.04 | V    |      |
|   | chiplevel  | T <sub>j</sub> = 150 °C |      | 0.88 | 0.98 | V    |
| r <sub>CE</sub> V <sub>GE</sub> = 15 V<br>chiplevel | GL .   | T <sub>j</sub> = 25 °C  |      | 5.4  | 7.7  | mΩ   |
|   | chiplevel  | T <sub>j</sub> = 150 °C |      | 8.8  | 10   | mΩ   |
| $V_{GE(th)}$  | $V_{GE}=V_{CE}, I_C = 6 \text{ mA}$  |                         | 5.5  | 6    | 6.5  | V    |
| I <sub>CES</sub>                                    | $V_{GE} = 0 V$   | T <sub>j</sub> = 25 °C  |      |      | 0.3  | mA   |
| V <sub>CE</sub> = 1200 V                            | V <sub>CE</sub> = 1200 V   | T <sub>j</sub> = 150 °C |      | -    |      | mA   |
| Cies  | V <sub>CE</sub> = 25 V<br>V <sub>GE</sub> = 0 V                                | f = 1 MHz               |      | 9.0  |      | nF   |
| Coes  |  | f = 1 MHz               |      | 0.89 |      | nF   |
| C <sub>res</sub>                                    |  | f = 1 MHz               |      | 0.88 |      | nF   |
| Q <sub>G</sub>                                      | V <sub>GE</sub> = - 8 V+ 15 V  |                         |      | 1650 |      | nC   |
| R <sub>Gint</sub>                                   | T <sub>j</sub> = 25 °C   |                         |      | 5.0  |      | Ω    |
| t <sub>d(on)</sub>                                  | $V_{CC} = 600 V$<br>$I_C = 150 A$<br>$V_{GE} = +15/-15 V$<br>$R_{Gon} = 1.5 Ω$ | T <sub>j</sub> = 150 °C |      | 258  |      | ns   |
| t <sub>r</sub>                                      |  | T <sub>j</sub> = 150 °C |      | 32   |      | ns   |
| Eon   |  | T <sub>j</sub> = 150 °C |      | 13.5 |      | mJ   |
| t <sub>d(off)</sub>                                 | $R_{G off} = 1.5 \Omega$   | T <sub>j</sub> = 150 °C |      | 388  |      | ns   |
| t <sub>f</sub>                                      | di/dt <sub>on</sub> = 5400 A/ $\mu$ s  | T <sub>j</sub> = 150 °C |      | 62   |      | ns   |
| E <sub>off</sub>                                    | di/dt <sub>off</sub> = 1800 A/μs<br>du/dt = 8100 V/μs                          | T <sub>j</sub> = 150 °C |      | 14.2 |      | mJ   |
| R <sub>th(j-c)</sub>                                | per IGBT   | I                       |      |      | 0.19 | K/W  |



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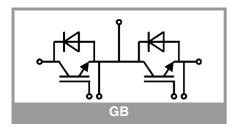
### **Typical Applications\***

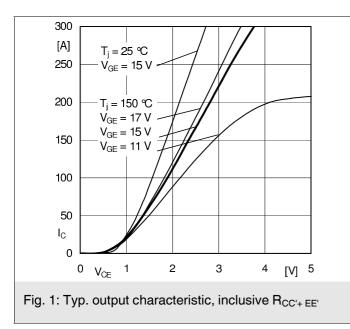
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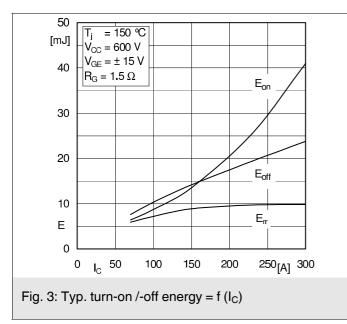
#### Remarks

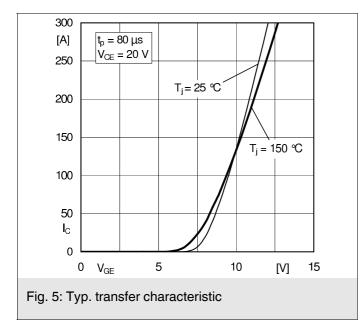
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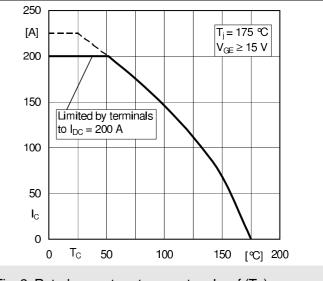
| Characte             | ristics  |                         |      |      |      |      |
|----------------------|--|-------------------------|------|------|------|------|
| Symbol               | Conditions   |                         | min. | typ. | max. | Unit |
| Inverse di           | iode   |                         |      |      |      |      |
| $V_F = V_{EC}$       | $V_{F} = V_{EC} \qquad I_{F} = 150 \text{ A}$ $V_{GE} = 0 \text{ V}$ chiplevel   | T <sub>j</sub> = 25 °C  |      | 2.14 | 2.46 | V    |
|                      |  | T <sub>j</sub> = 150 °C |      | 2.07 | 2.38 | V    |
| V <sub>F0</sub>      | chiplevel  | T <sub>j</sub> = 25 °C  |      | 1.30 | 1.50 | V    |
|                      |  | T <sub>j</sub> = 150 °C |      | 0.90 | 1.10 | V    |
| r <sub>F</sub>       | chiplevel  | T <sub>j</sub> = 25 °C  |      | 5.6  | 6.4  | mΩ   |
|                      |  | T <sub>j</sub> = 150 °C |      | 7.8  | 8.5  | mΩ   |
| I <sub>RRM</sub>     | $      I_F = 150 \text{ A} \\            di/dt_{off} = 5800 \text{ A}/\mu\text{s} \\            V_{GE} = \pm 15 \text{ V} \\            V_{CC} = 600 \text{ V} $ | T <sub>j</sub> = 150 °C |      | 165  |      | Α    |
| Q <sub>rr</sub>      |  | T <sub>j</sub> = 150 °C |      | 22   |      | μC   |
| E <sub>rr</sub>      |  | T <sub>j</sub> = 150 °C |      | 8.5  |      | mJ   |
| R <sub>th(j-c)</sub> | per diode  | <u> </u>                |      |      | 0.31 | K/W  |
| Module               |  |                         |      |      |      |      |
| L <sub>CE</sub>      |  |                         |      | 30   |      | nH   |
| R <sub>CC'+EE'</sub> | measured per<br>switch   | T <sub>C</sub> = 25 °C  |      | 0.65 |      | mΩ   |
|                      |  | T <sub>C</sub> = 125 °C |      | 1.09 |      | mΩ   |
| R <sub>th(c-s)</sub> | calculated without thermal coupling $(\lambda_{grease}=0.81 \text{ W}/(\text{m}^{*}\text{K}))$   |                         |      | 0.04 | 0.05 | K/W  |
| Ms                   | to heat sink M6  |                         | 3    |      | 5    | Nm   |
| Mt                   |  | to terminals M5         | 2.5  |      | 5    | Nm   |
|                      |  |                         |      | -    |      | Nm   |
| w                    | 1  |                         | İ    |      | 160  | g    |

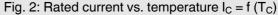


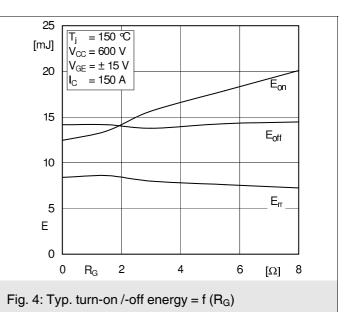


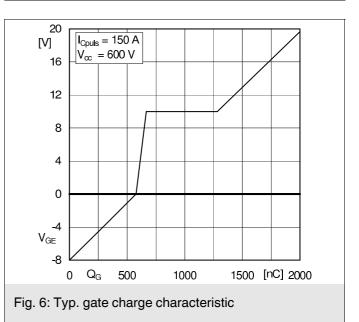


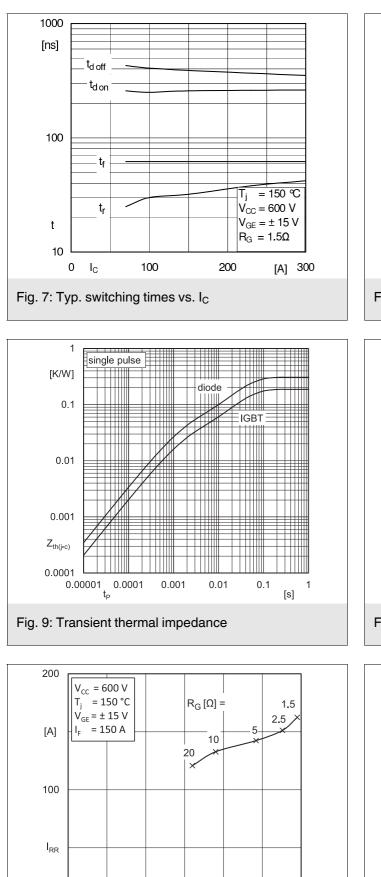


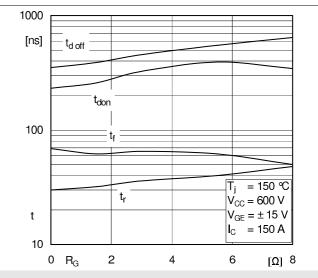


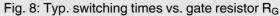


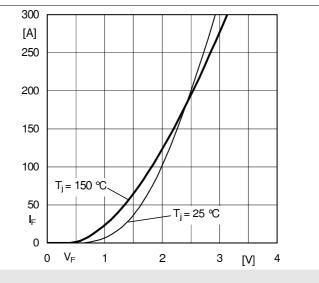


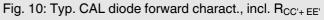












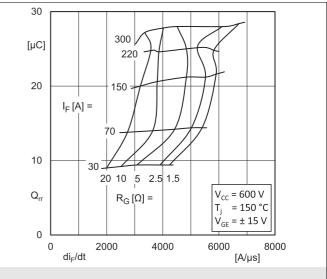


Fig. 12: Typ. CAL diode peak reverse recovery charge

0

0

di<sub>F</sub>/dt

2000

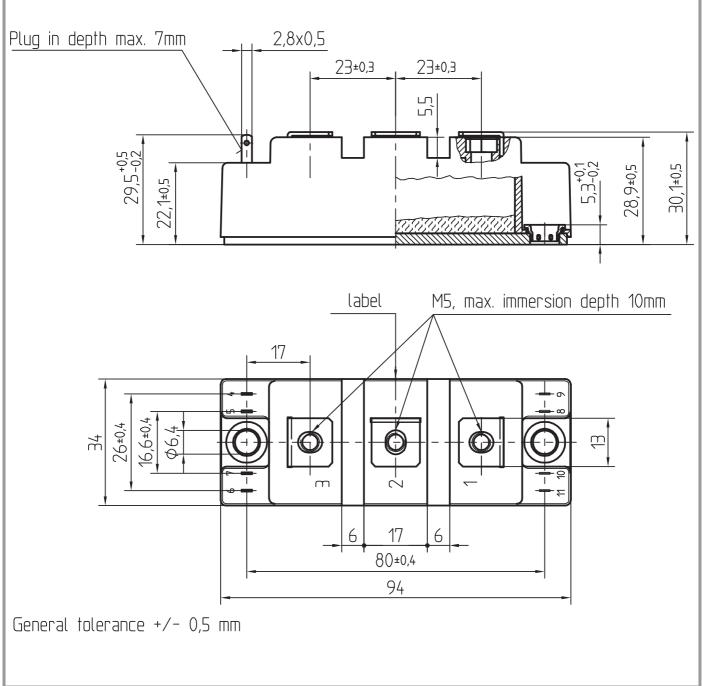
Fig. 11: CAL diode peak reverse recovery current

4000

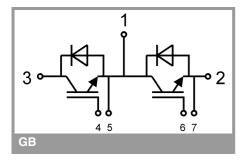
[A/µs]

6000

Dimensions in mm



**SEMITRANS 2** 



This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, chapter IX.

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